4/17/2012

RELIABILITY MONITOR REPORT
FOR

Dallas 0.35µm Silicon Gate CMOS (E35)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS1080CL

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 5288 QUANTITY: 45 FAILS: 0 FITS: 21.6

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

Process Information:

Process Description: Dallas 0.35µm Silicon Gate CMOS (E35)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1106	DS1080CL	125C, 3.6 VOLTS	1000 HRS	45	0	VD823625BB
				Total:		**0**	

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